



# BIG DATA IN REAL TIME: FAST AND FURIOUS

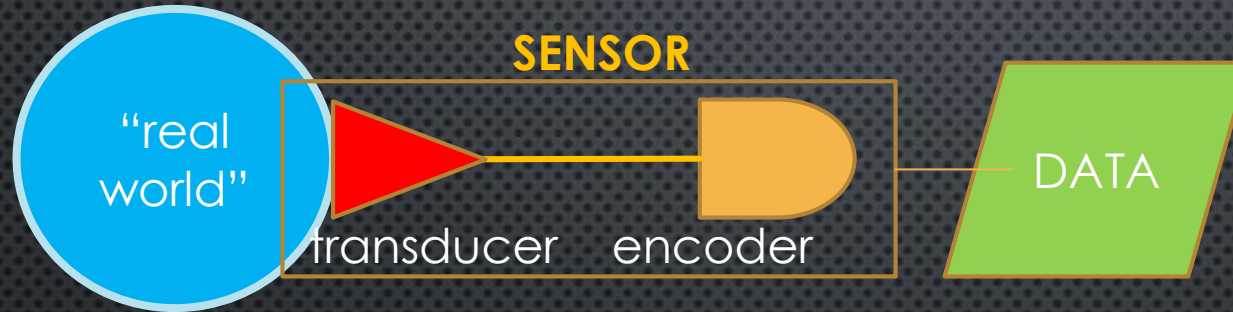
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# DATA OR BIG DATA?

- SENSORS PRODUCES DATA →
  - A SENSOR IS WHATEVER IS ABLE TO PRODUCE AN OBSERVABLE ENCODING EVENTS IN A GIVEN FORMAT



- TOO BIG FOR WHAT?
  - SENSORS PRODUCE DATA FASTER THAN WE CAN STORE
  - WE NEED TO INTERACT WITH DATA TO TAKE DECISIONS IN REAL TIME
- BIG IS A RELATIVE CONCEPT – NOT JUST A MATTER OF VOLUME
  - MORE THAN THE ABSOLUTE VOLUME THE SALIENCY MATTERS. MODEL DEPENDENT
  - SUCCESSFUL DATA REDUCTION MODEL ? → THERMODYNAMICS! A THERMOMETER IS A SMART SENSOR





# BIG DATA: NOT ALL THE SAME:

Data model complexity

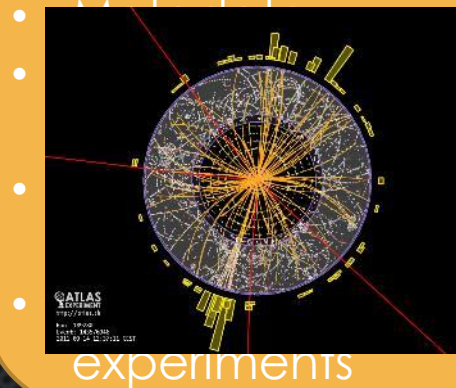
## Structured

Data uses:  
Homogeneous and fixed data with a wide range of variability:  
• A phone directory  
• measurements



- Data model fixed
- Small parametric space to represent the data
- Prevalent deduction based analysis

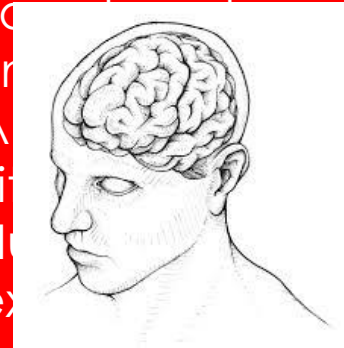
## Multi-Structured /Hybrid



- Data model evolving with data
- Variable parametric space
- Data driven induction and deduction

## Free-structured

Data uses:  
• Empirical data  
• Analogical data  
• Literature  
• Historical examples  
• Scientific models



- Data model evolving with experience
- morphing parametric space
- Analogy based induction and deduction



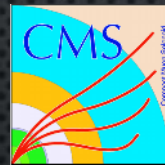
# DATA INTENSITY AND DATA RATE: FAST AND FURIOUS

[HEP may have something to say!]

- THE DATA VOLUME CAN BE DRIVEN BY SCATTERED OR CONCENTRATED SENSOR SYSTEMS
  - GEOGRAPHICALLY SCATTERED DATA SOURCES → LOW DENSITY MANAGED THROUGH DATA LOGISTICS NETWORKS. THE REMOTE TERMINALS ARE SMART FRONT END



- CONCENTRATED SENSORS EACH PRODUCING HIGHER THAN MANAGEABLE DATA FLOW?  
A PARTICLE PHYSICS EXPERIMENT AT LHC FOR EXAMPLE...



- SEARCH FOR A NEEDLE IN THE STRAW
- NEED FOR SELECTION AT SENSOR LEVEL → TRIGGER CONCEPT

- FAST AND SMART PROCESSING TO TAKE A FAST DECISION IN REAL TIME, AT NS SCALE..., **FAST AND FURIOUS**

For the HEP people this is a MUST since ever.

**Why all this hurry??**

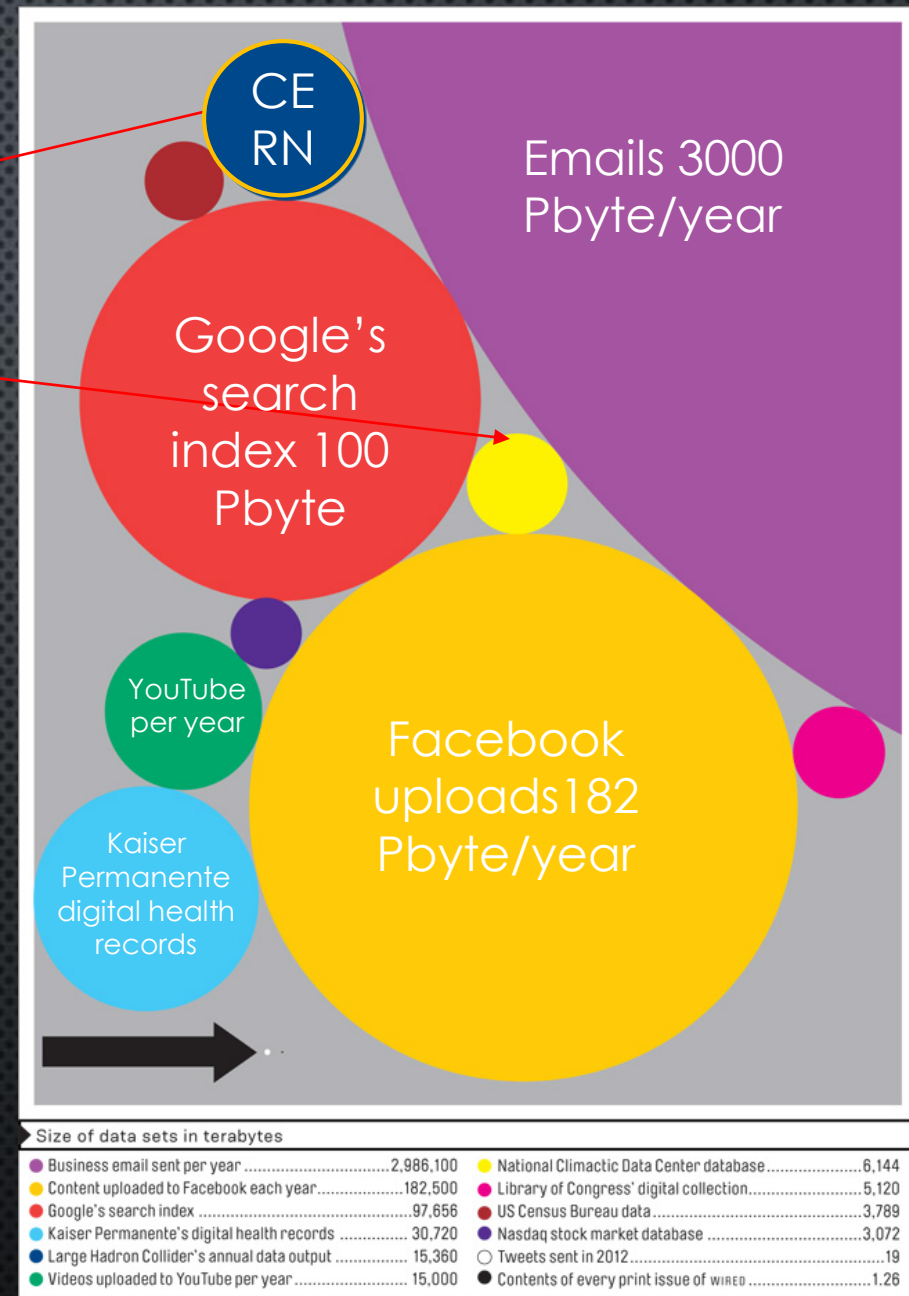
Well, to avoid an experiment running 100 years....



# REALLY BIG DATA

- CERN "CLASSIC" BIG DATA 15 PBYTE/YEAR
- THIS IS AFTER THE TRIGGER SELECTING  $1/(4 \cdot 10^4)$
- THE REAL DATA ARE THEN 600 EXA BYTE/YEAR
- 19 PBYTE FROM A SINGLE SOURCE

**MUST BE TREATED AT THE SOURCE**





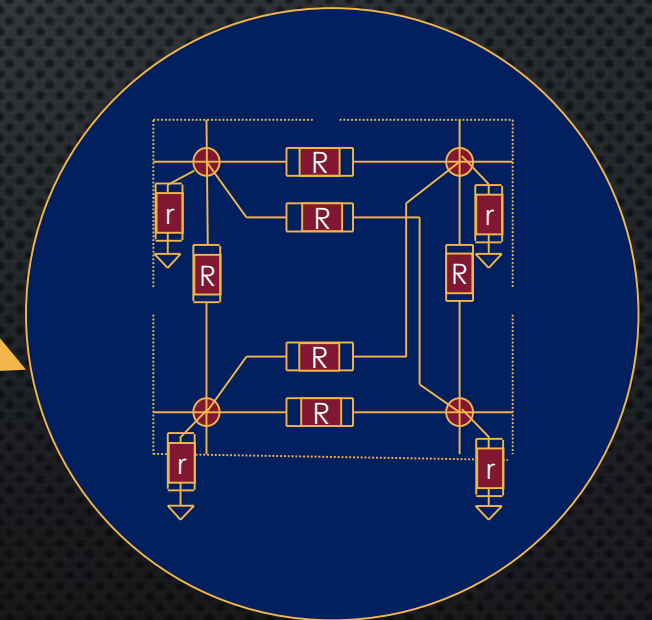
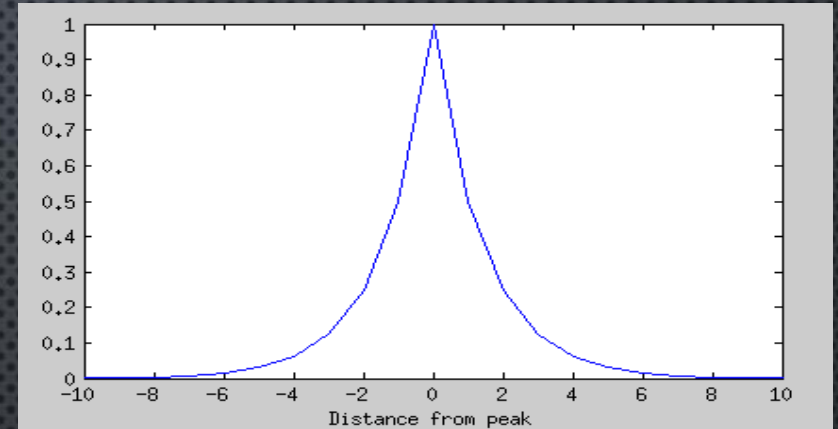
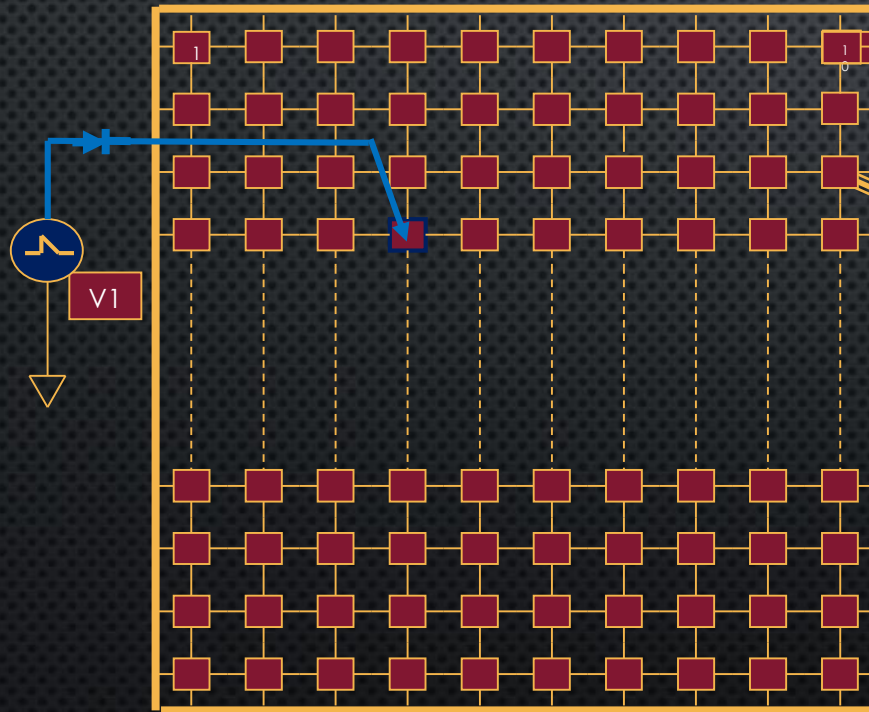
# HEP COMMUNITY AWARENESS AT THE DAWN OF ICT ERA

- IN THE '80 A BIG EFFORT STARTED TO SOLVE THE PROBLEM OF FAST PATTERN RECOGNITION AND NEURAL NETWORKS
  - RISTORI ET AL. ASSOCIATIVE MEMORIES (AM CHIP)
  - DARBO ET AL. CONTIGUITY PROCESSOR
  - AA.VV. START OF STUDIES ON NEURAL NETWORK ALGORITHMS FOR TRACKING
  - AA.VV. FUZZY LOGIC
- MODERN TRACKING TRIGGERS WOULD LIKE TO:
  - SUPPRESS THE NOISE
  - RECONSTRUCT THE TRACK ELEMENTS
  - CLASSIFY MEANINGFUL EVENTS THROUGH TOPOLOGY
- A REGRESSION IS THE BEST WAY TO EVALUATE DATA AGAINST A MODEL → COMPUTATION COMPLEXITY



# WEIGHTING RESISTIVE MATRIX: LET THE PHYSICS COMPUTE

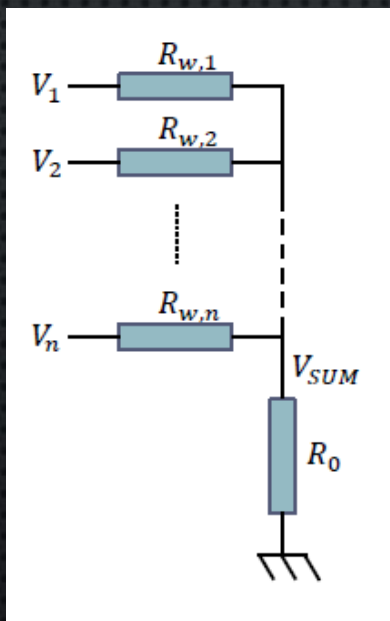
- AN INTERCONNECTED REPETITIVE RESISTIVE NETWORK SUBJECTED TO AN ELECTROSTATIC POTENTIAL PROVIDES THE NECESSARY TOOLS
  - THE DIFFUSION POTENTIAL AS A NOTION OF DISTANCE
  - THE SUPERPOSITION PRINCIPLE ENSURES THE CORRELATION





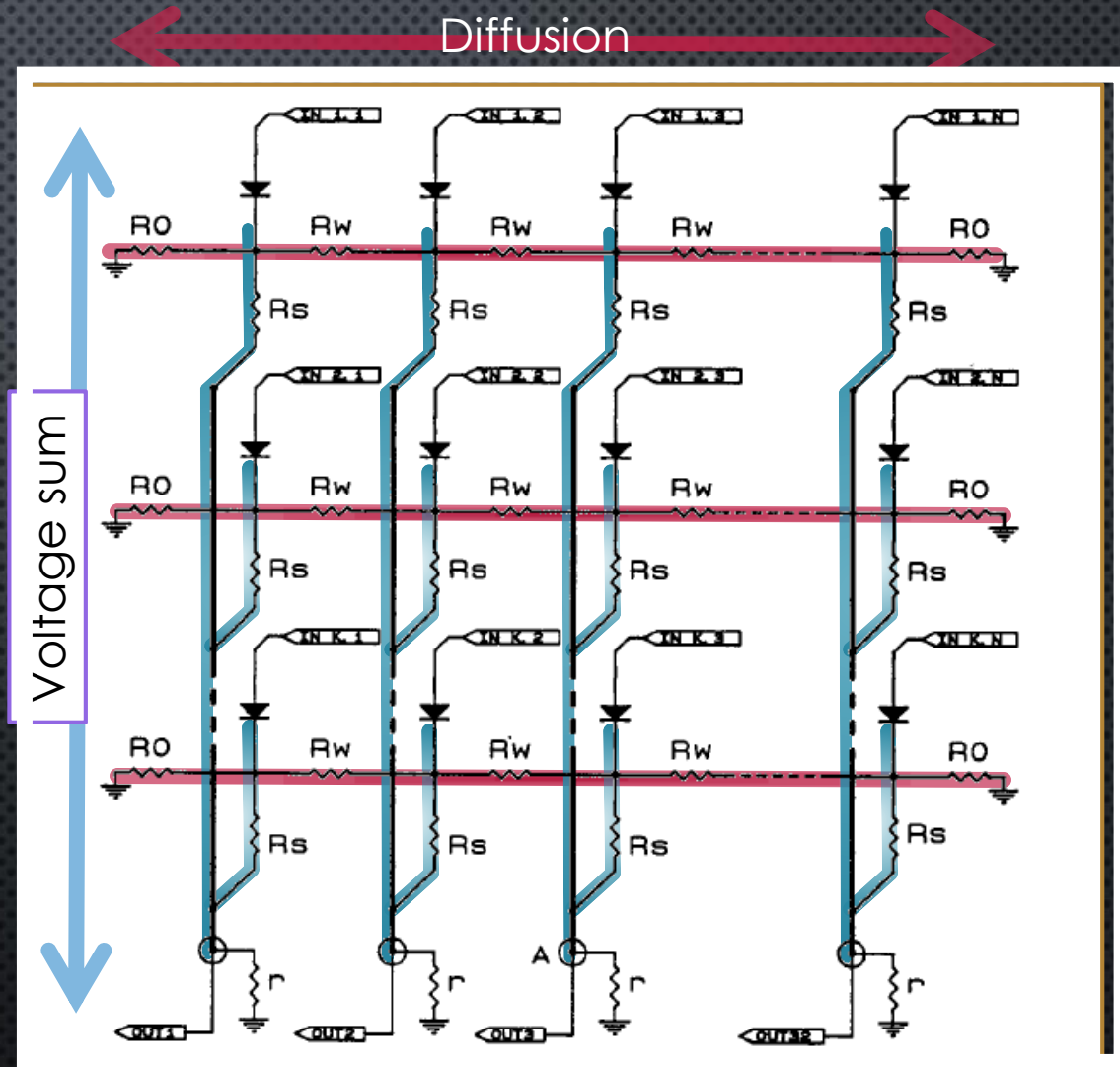
# THE WRM SCHEMA – A SIMPLE 1D IMPLEMENTATION

- FROM: R. CARDARELLI ET AL.; “ON A VERY FAST TOPOLOGICAL TRIGGER”; NIM A324(1993) 253-259
- A VIRTUALLY INFINITE RESISTIVE NETWORK, WHERE THE RATIO  $R_w/R_s$  DETERMINES THE EXPONENTIAL VOLTAGE DIFFUSION RATE



If  $R_0 \ll \min(R_{w,1}, \dots, R_{w,n})$

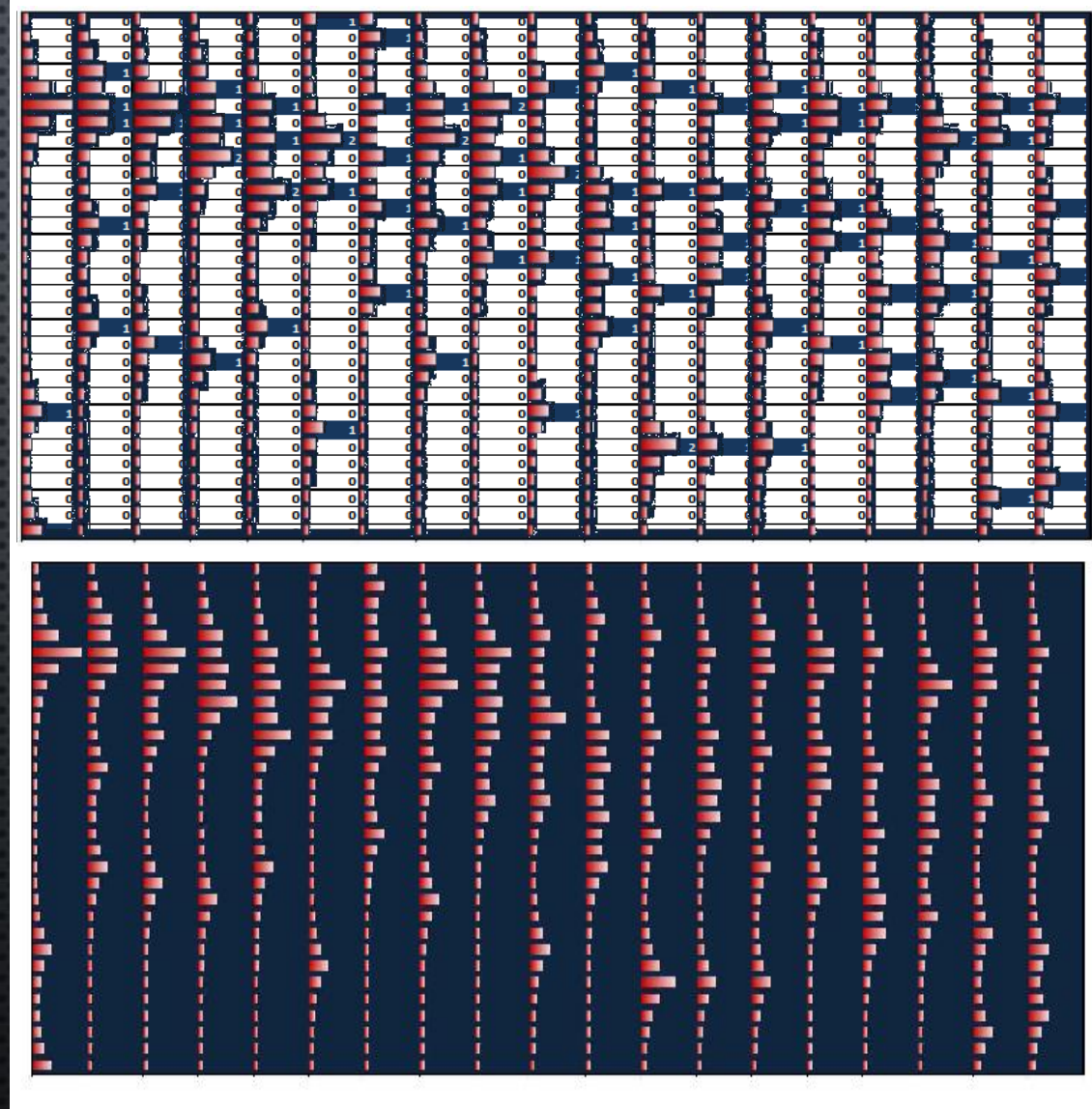
$\rightarrow V_{SUM} = w_1 V_1 + w_2 V_2 + \dots + w_n V_n$





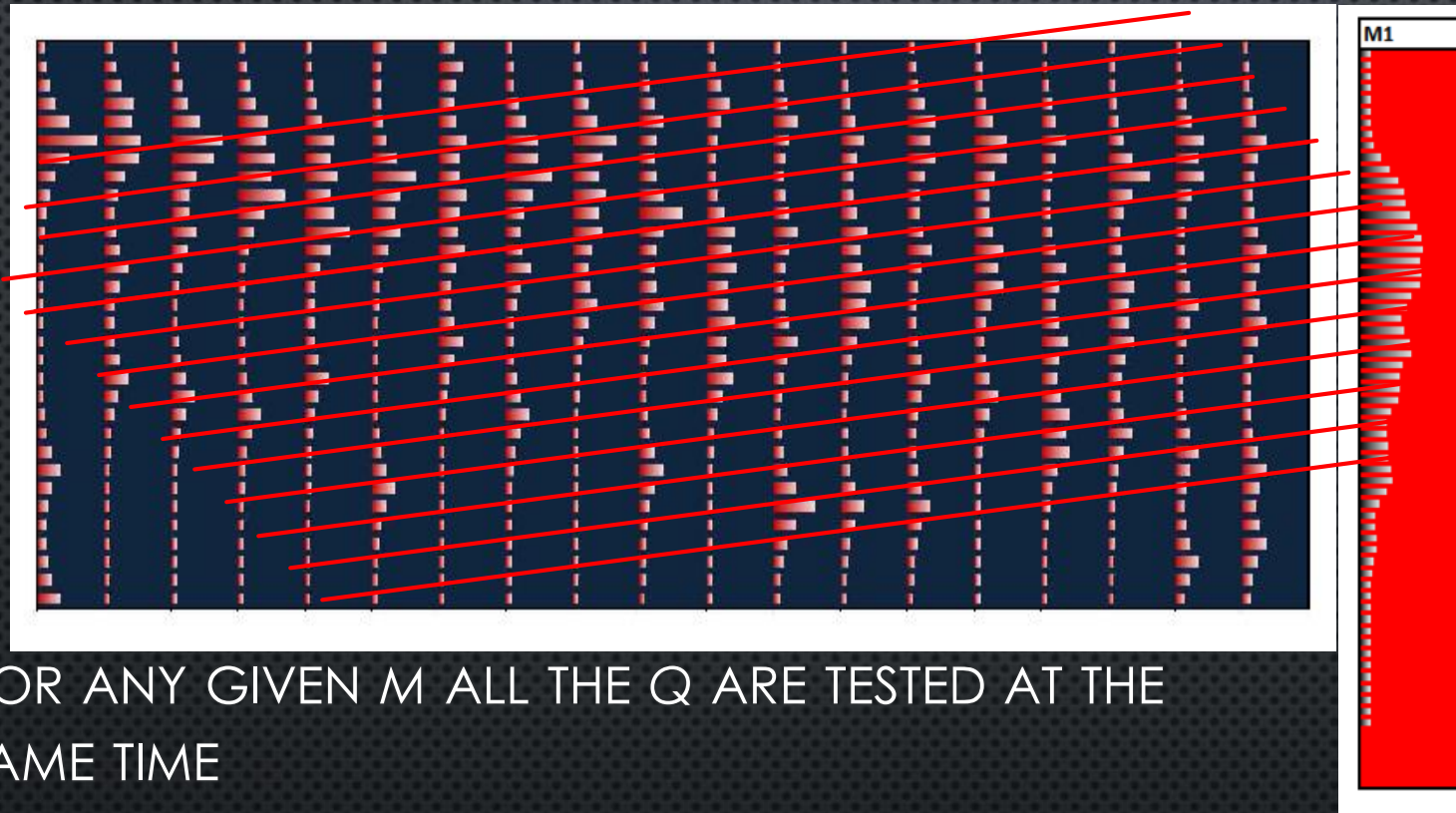
# WRM EXERCISE: 3 TRACK VERTEX WITH NOISE

- UPPER IMAGE IS THE DIGITAL INPUT TO THE WRM.
- CAN BE ANY DIGITAL READOUT DETECTOR
- LOWER IMAGE IS THE CORRESPONDING POTENTIAL DISTRIBUTION PRODUCED BY THE WRM.





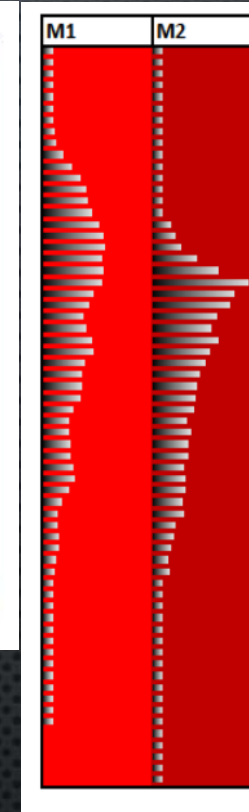
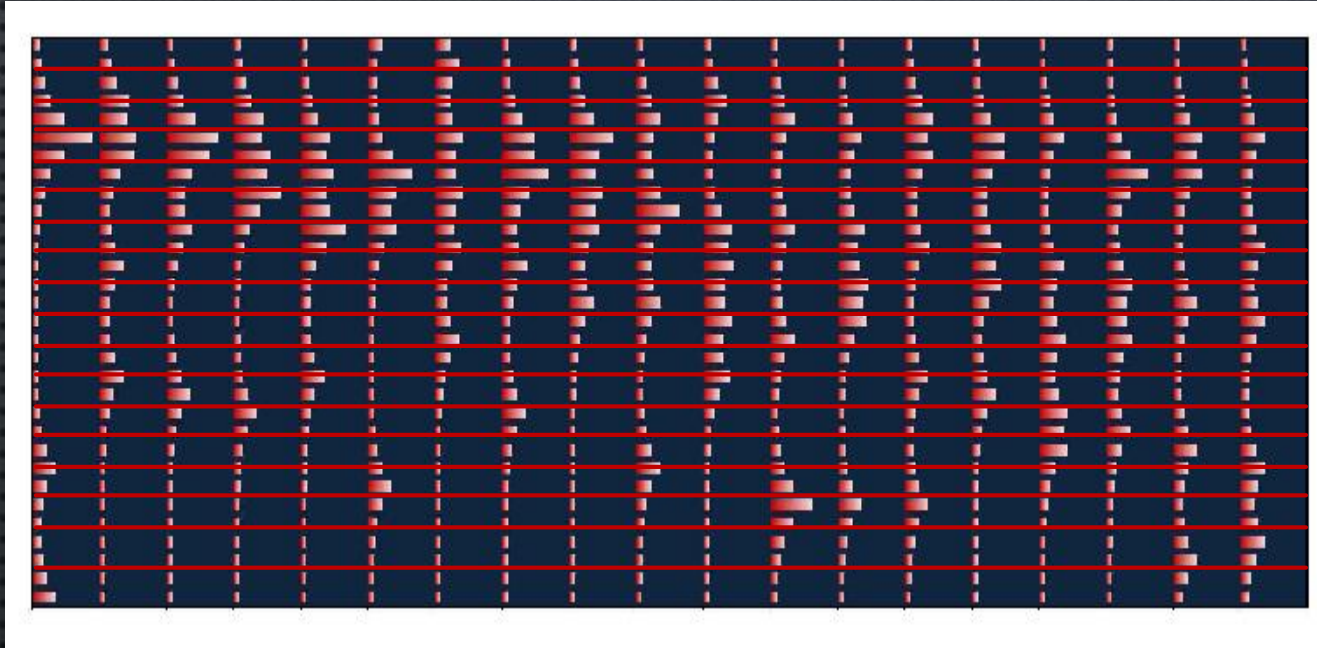
# STRAIGHT LINE FIT: $Y=MX+Q$



- FOR ANY GIVEN M ALL THE Q ARE TESTED AT THE SAME TIME



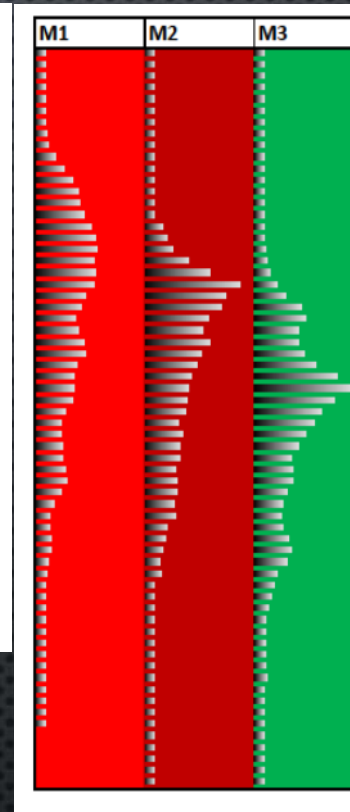
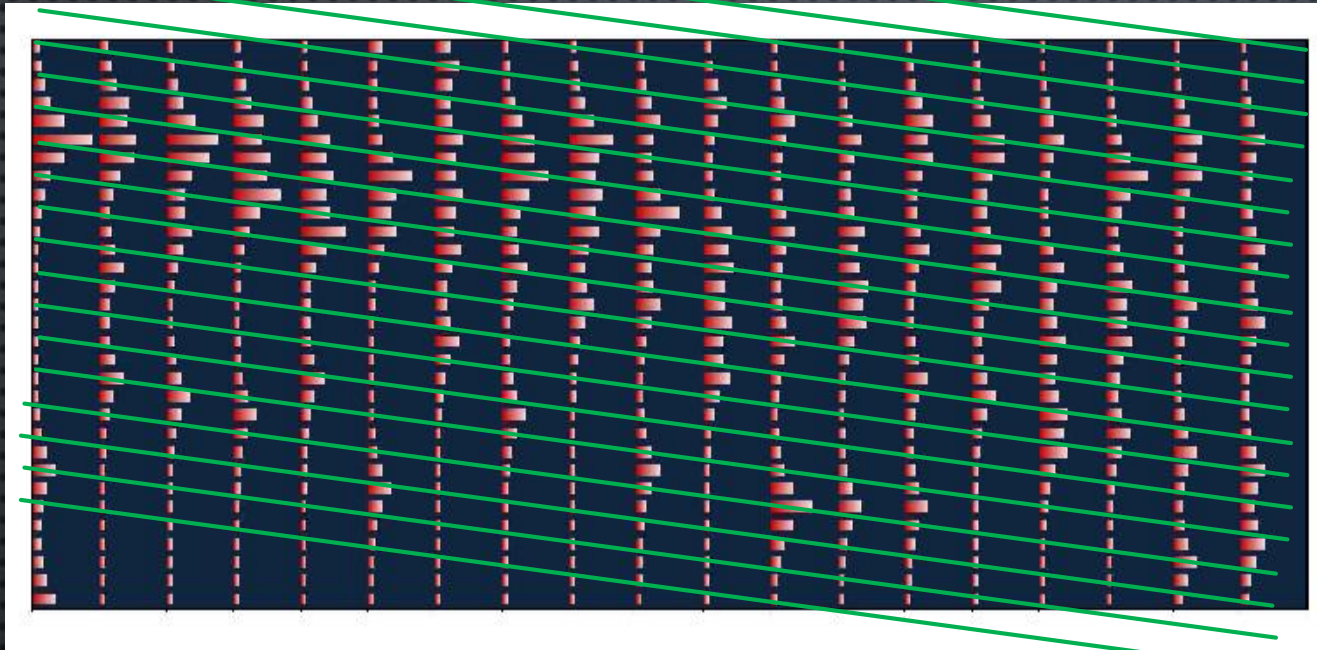
# STRAIGHT LINE FIT: $Y=MX+Q$



- FOR ANY GIVEN M ALL THE Q ARE TESTED AT THE SAME TIME
- A GOOD M,Q CHOICHE PRODUCE A SHARPER AND HIGHER PEAK IN THE PARAMETER SPACE



# STRAIGHT LINE FIT: $Y=MX+Q$

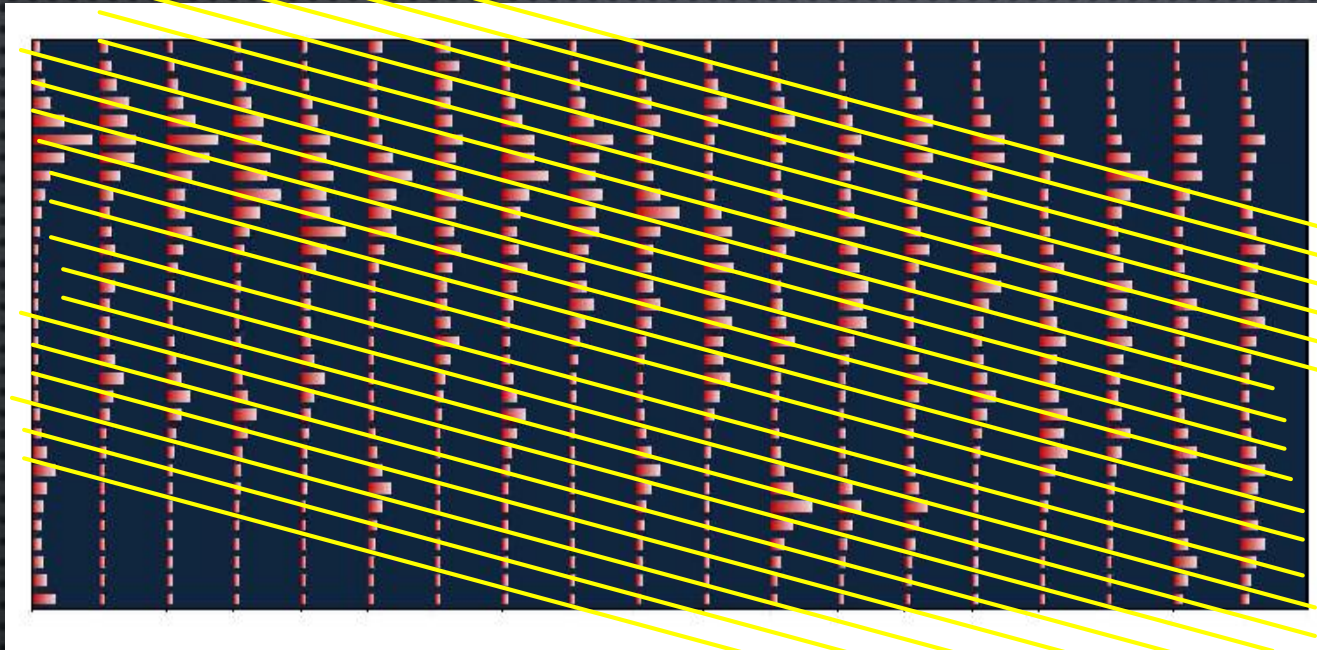


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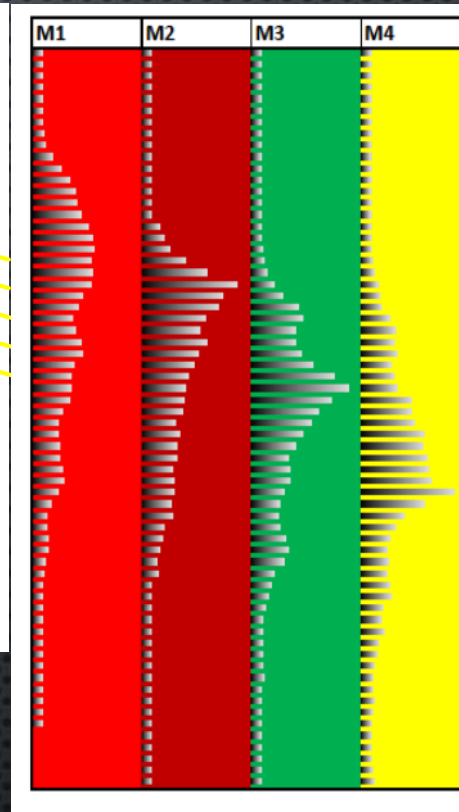
The test can be done in parallel or the data are feed to the matrix by a circular buffer



# STRAIGHT LINE FIT EXAMPLE: $Y=MX+Q$



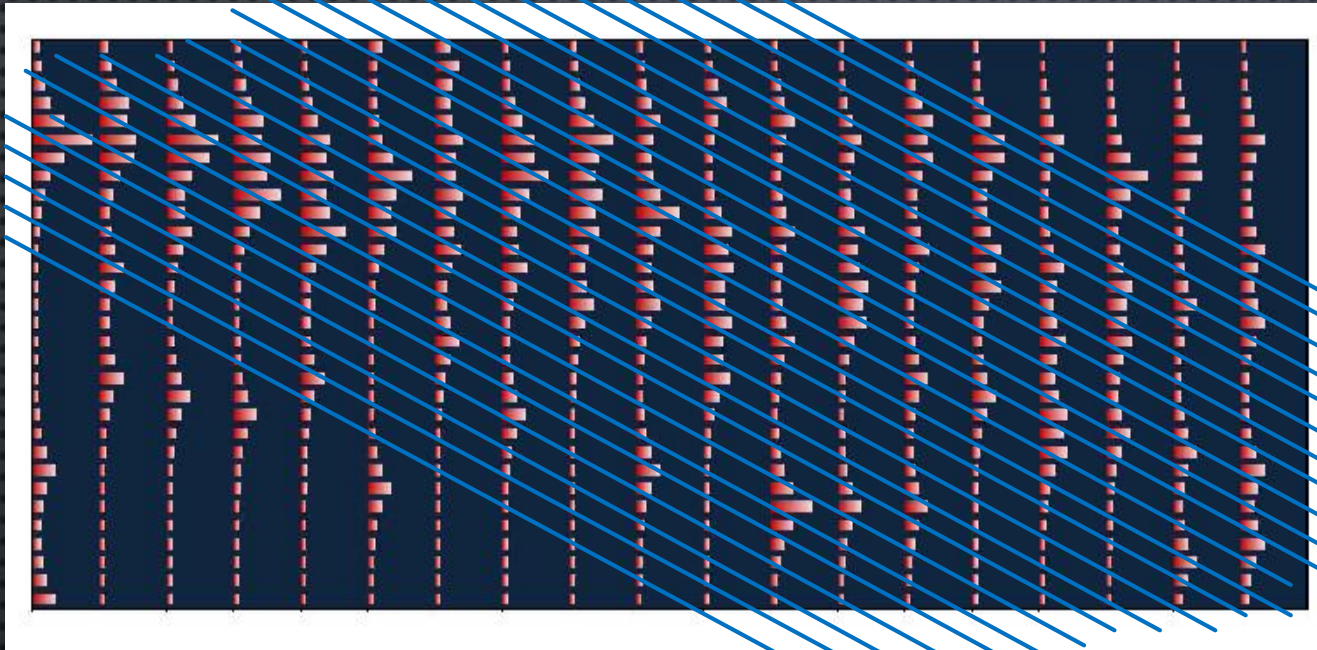
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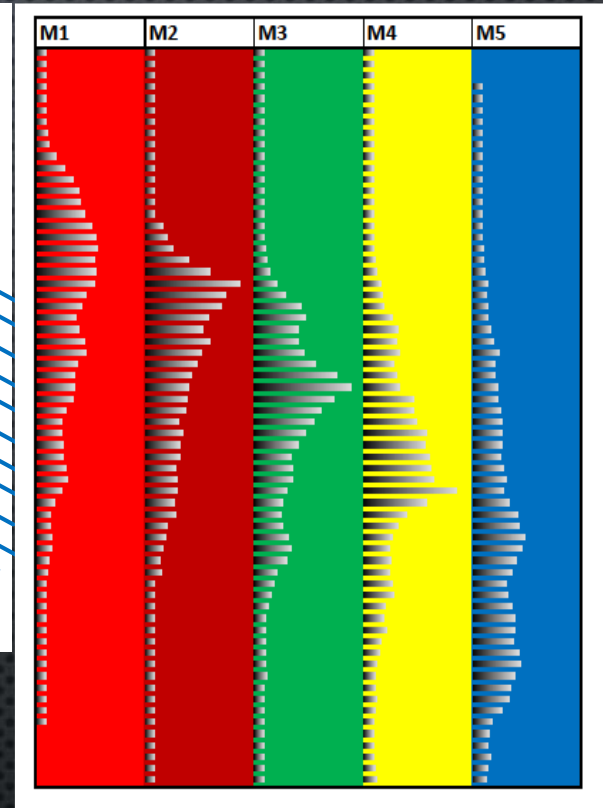
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# STRAIGHT LINE FIT EXAMPLE: $Y=MX+Q$



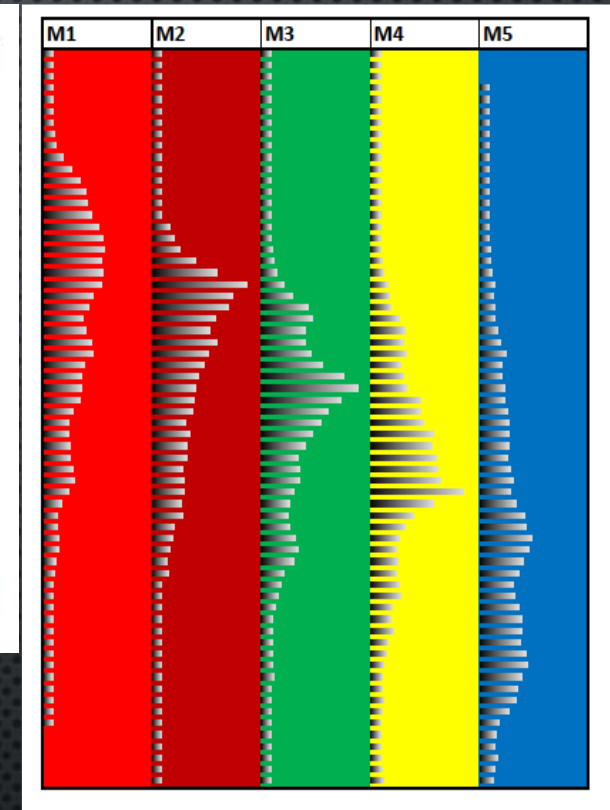
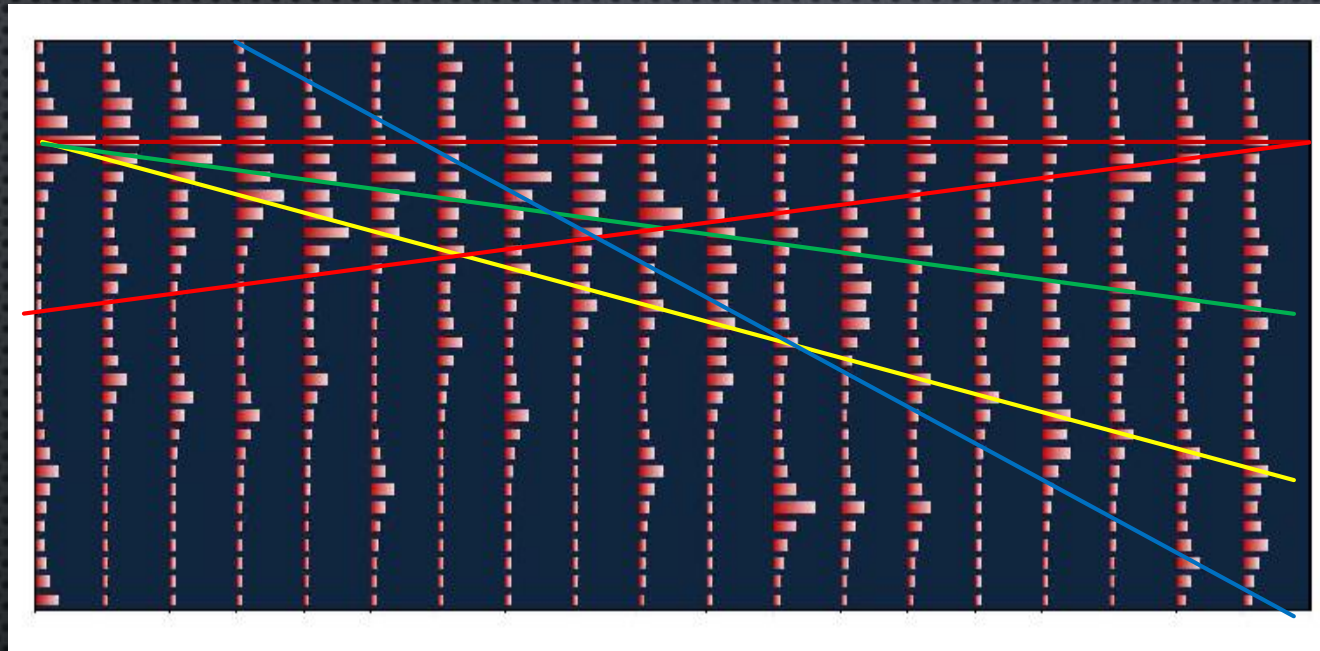
- FOR ANY GIVEN M ALL THE Q ARE TESTED AT THE SAME TIME
- A GOOD M,Q CHOICHE PRODUCE A SHARPER AND HIGHER PEAK IN THE PARAMETER SPACE
- IN THE OTHER CASES THE DISTRIBUTION IS FLAT



The test can be done in parallel or the data are feed to the matrix by a circular buffer



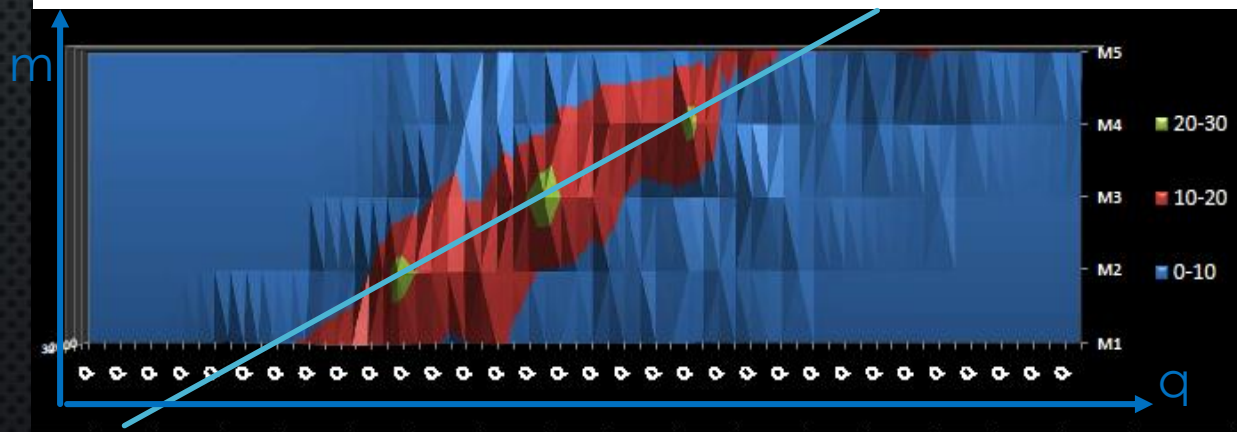
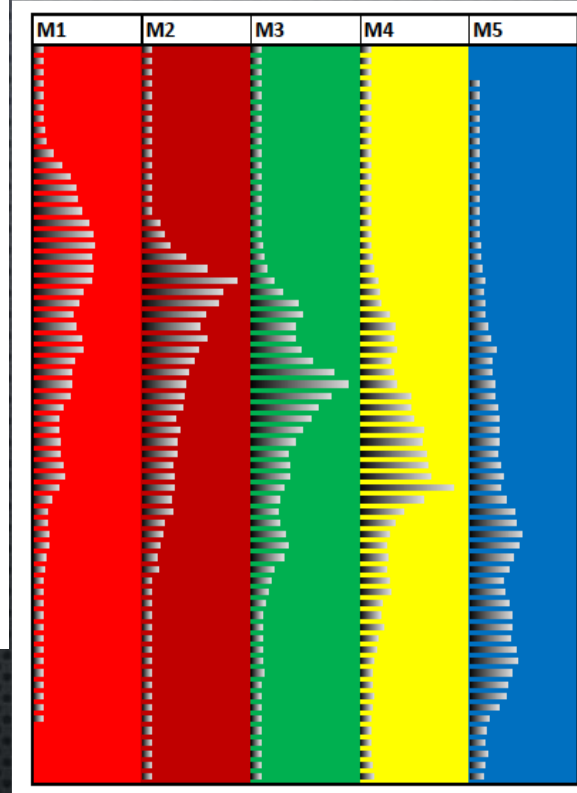
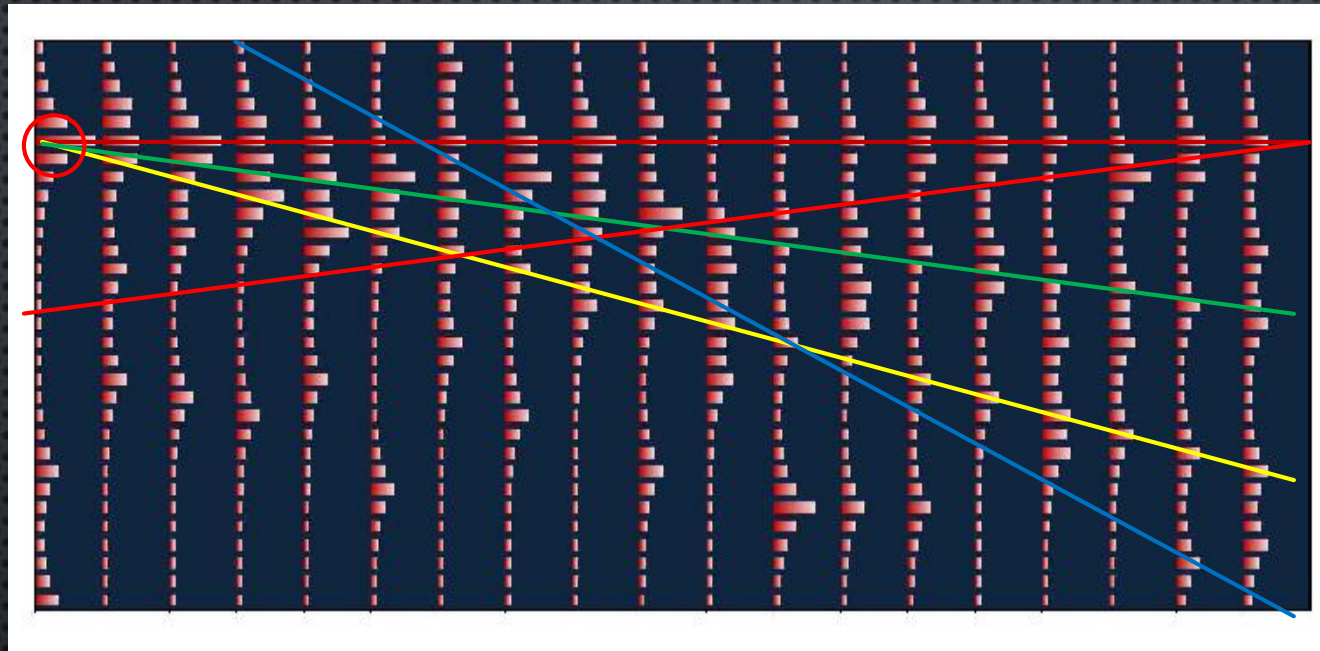
# VERTEX IDENTIFICATION EXAMPLE



- ▶ The 5 tested  $m$  values displayed as a function of  $q \rightarrow$  local maximum
- ▶ The three highest peaks are selecting lines crossing in the same point (vertex)
- ▶ In the  $(m, q)$  space 3 aligned points represent a vertex  $\rightarrow$  vertex signature



# STRAIGHT LINE FIT EXAMPLE: $Y=MX+Q$



We can treat the parametric plane as new input data  $\rightarrow$  in the new parametric plane  $m', q'$  of the line represents the vertex

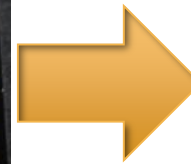


# FROM PARTICLE TRACKS TO FAST IMAGE ANALYSIS

- THE IDEA: IN HEP WE CAN RECOGNIZE SIMPLE 1D TRAJECTORIES IN  $\sim 10^{-9}$  s
- IN COMPUTER VISION WE NEED TO PROCESS 1 M PIXEL IN  $\sim 10^{-2}$  s
- WE CAN USE  $10^7$  LONGER TIME TO PERFORM MUCH COMPLEX PATTERN RECOGNITION
- REBUILD THE IMAGE STRUCTURES IN TERMS OF A PARAMETRIC REPRESENTATION OF ITS ELEMENTS

Present WRM  
limitations

- 20 years old IC
- Digital input
- 1D diffusion
- 8x8 inputs only



- New tech  $\rightarrow$  faster speed
- Integrated to the sensor
- 3D diffusion
- Programmable matrix size

What we can dream of?



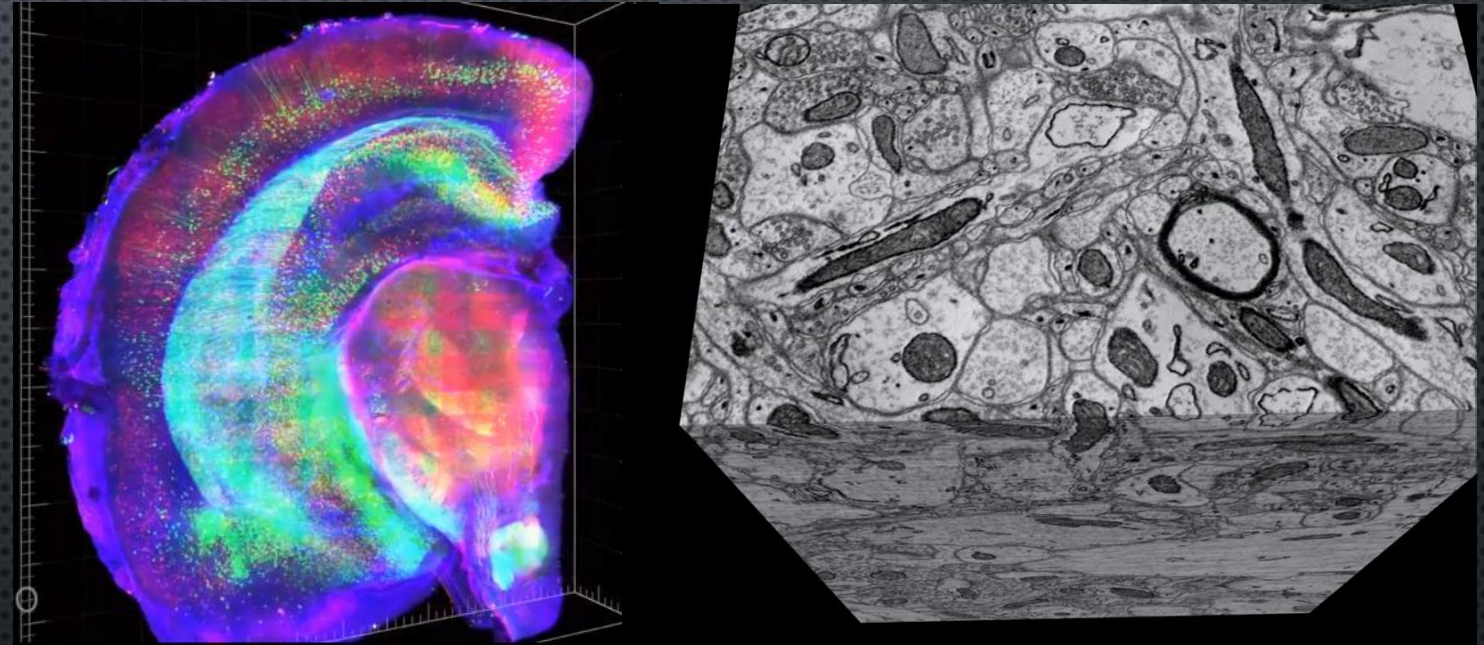
# FROM FRONTIER SCIENCE TO FRONTIER PROBLEMS

DREAM APPLICATIONS WITH A  
COMMON BOTTLENECK: **UNTREATABLE  
LOW DATA THROUGHPUT**

- REAL TIME PROCESSING FOR MEDICAL APPLICATIONS
- NEURON SYSTEMS READOUT

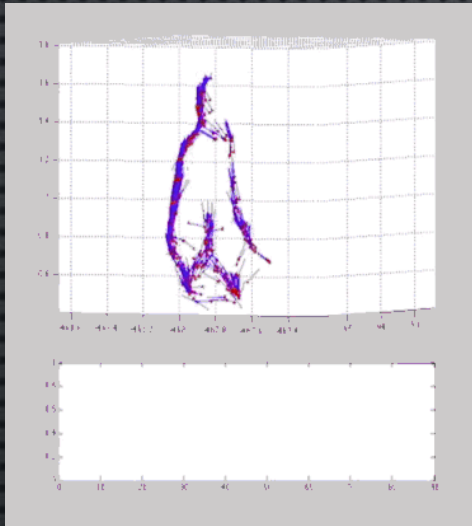
WORST THAN EVER: **LOW POWER  
CONSTRAINTS FOR MOBILE  
APPLICATIONS**

- AUTONOMOUS ROBOTS,
- SMART PROSTHESIS
- ...AND SELF DRIVING CARS

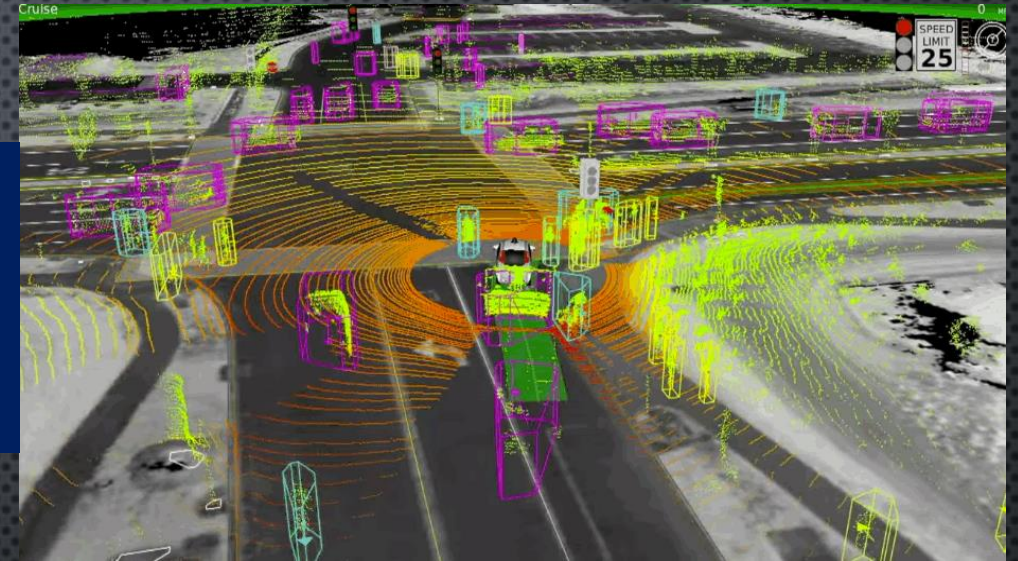




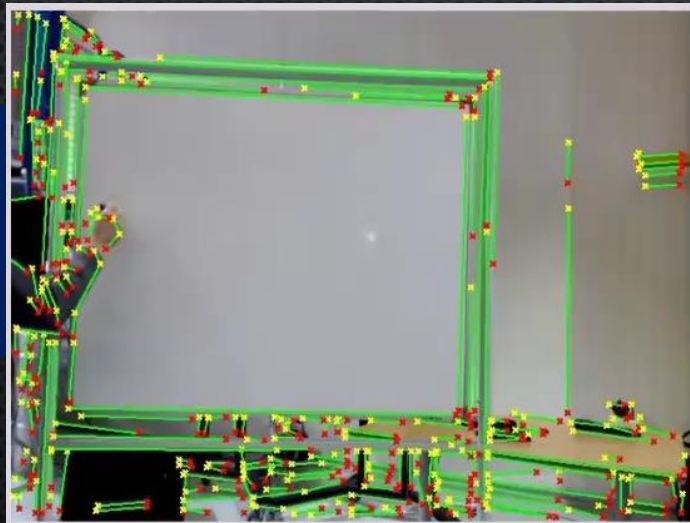
# FAST AND CAUTIOUS: CARS AND ROBOTS



How the Google Car sensors see the world



How the a simple WRM sees objects through lines



Fast light and low power smart Front End is what would enable mobile smart devices challenge: low weight low power high performance.

We propose to develop the next generation of WRM structures to face this challenge



THANK YOU FOR THE ATTENTION

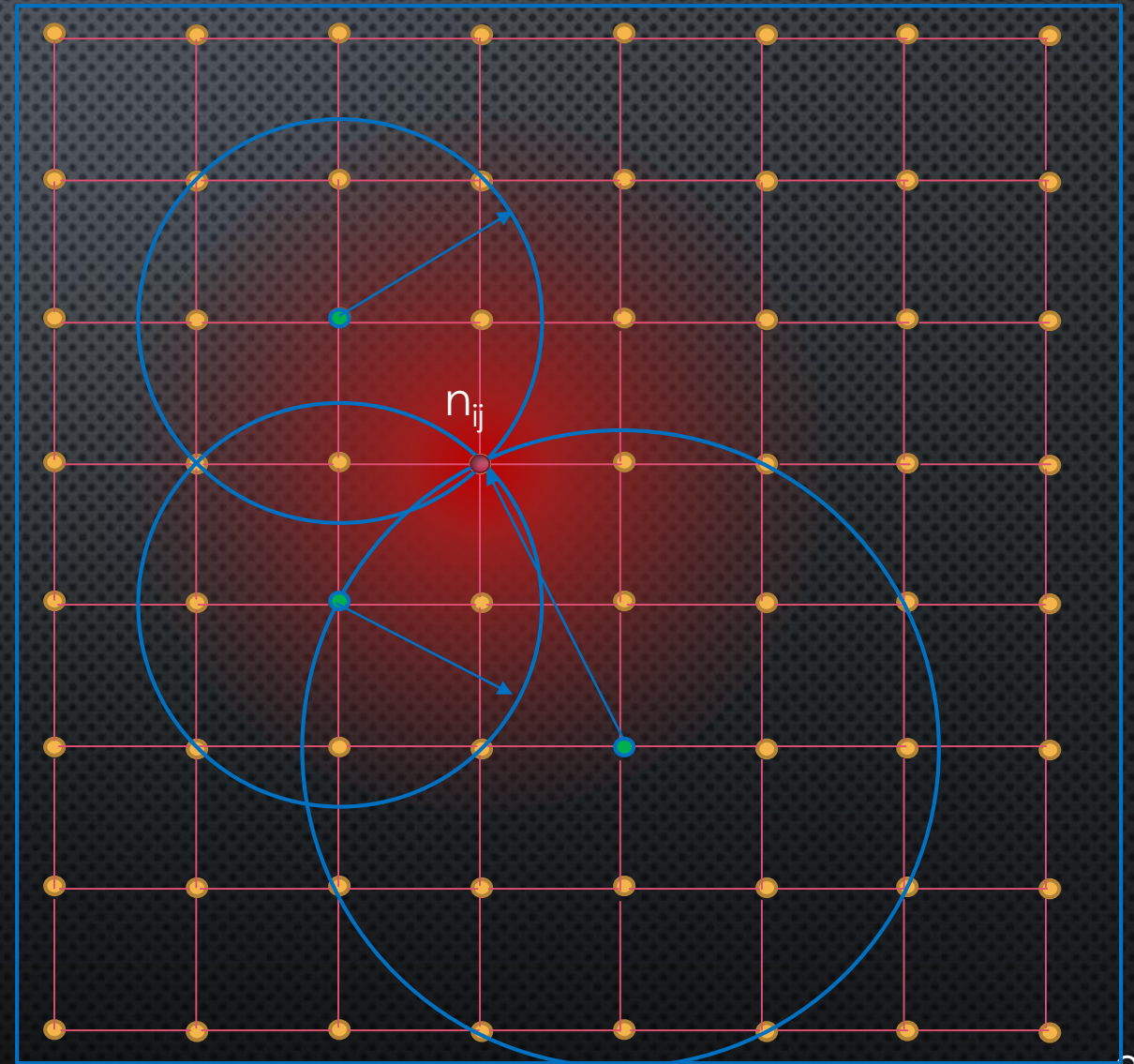


# BACKUP



# WEIGHTING RESISTOR MATRIX (WRM) CONCEPT

- A GIVEN NODE  $N_{ij}$  IS SET TO A POTENTIAL  $V$  WHICH IS DIFFUSED TO THE NEIGHBORING NODES WITH A LAW:
  - $V_{kl} = (1/W) |N_{ij} - N_{kl}|$
  - $W$  IS THE DIFFUSION CONSTANT WHICH DEPENDS ON THE RESISTIVE PARTITION
  - $V_{kl}$  IS CORRELATED TO THE DISTANCE
- BY MEASURING IN 3 POINT  $V$  IT IS POSSIBLE TO DETERMINE THE POSITION OF  $N_{ij}$
- BY MEANS OF AN APPROPRIATE SET OF MEASUREMENT IT IS POSSIBLE TO EXTRACT INFORMATION ON THE POINT POSITION
- **HOW TO EXTRACT GLOBAL INFORMATION ABOUT A PATTERN OF POINTS?**



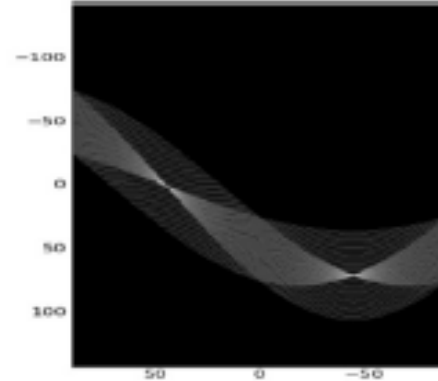


# Hough Transform

Describe straight lines in polar coordinates,  
 $x\cos(\theta) + y\sin(\theta) = r$ . For any "on" pixel  $(x_0, y_0)$ , compute a set of possible  $(\theta_i, r_i)$ .



(a) Input



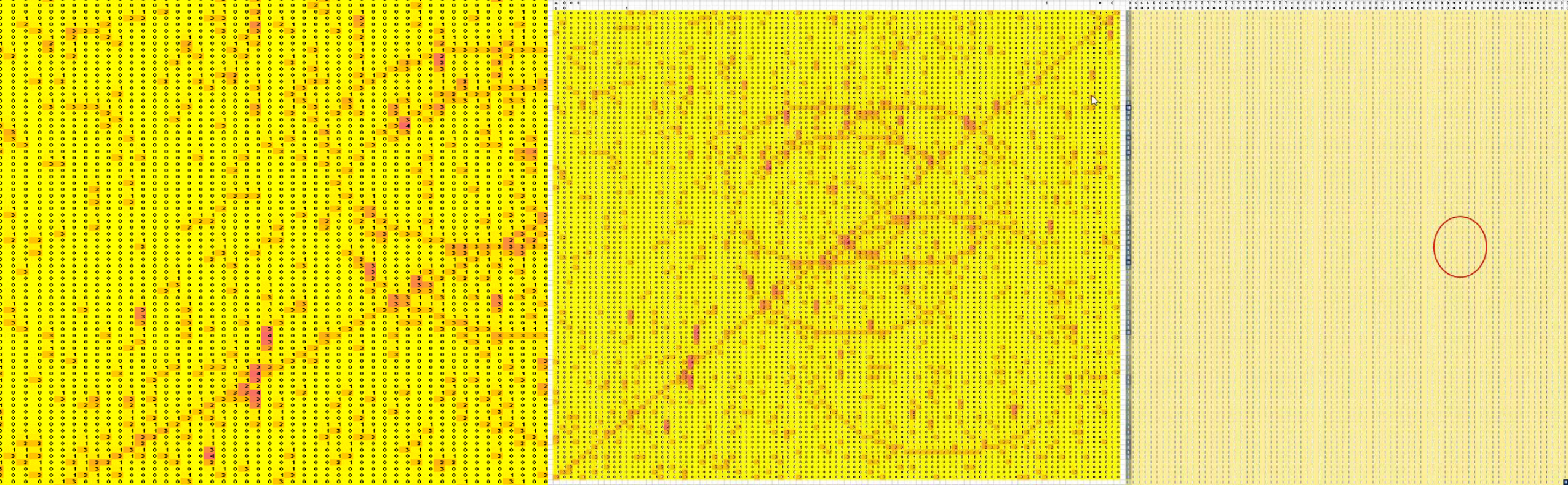
(b) Hough



(c) Detected lines



# SIMULATION OF 100X100 PIXEL MATRIX

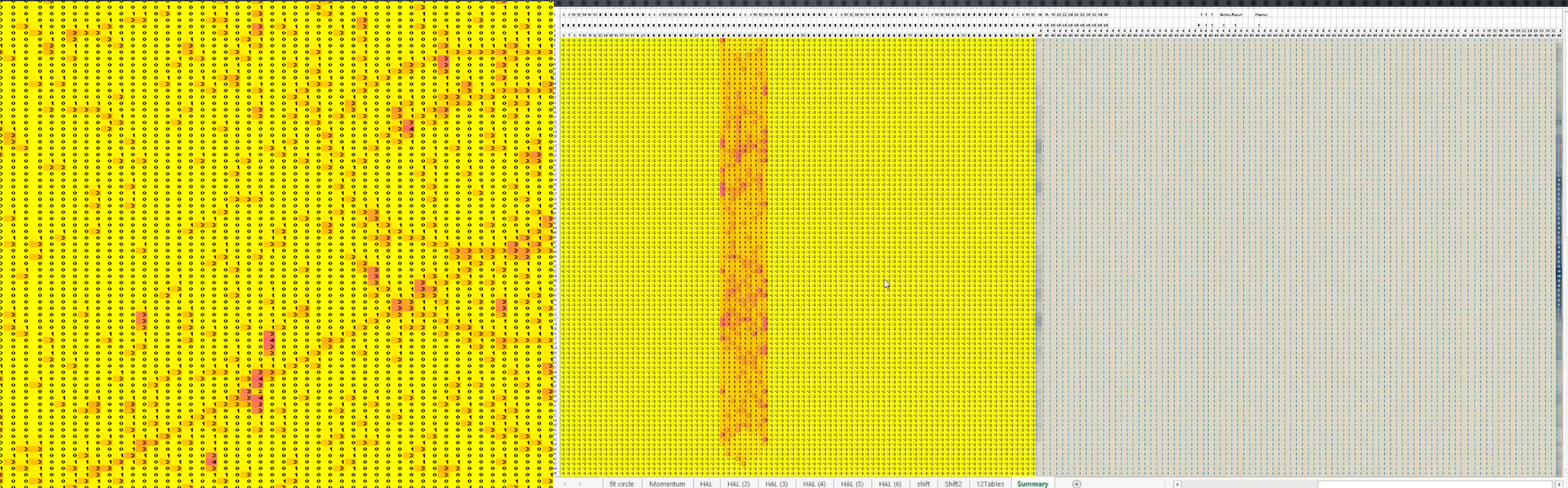


CRUCIAL: S/N increases with resolution  $\rightarrow$  increase the number of degrees of freedom of the fit

- Shown how the data transform in the connection space
- $m$  is looping  $\{0 \dots 2\}$  in steps of 0.1
- Each  $m$  test is a column inserted in the parametric space



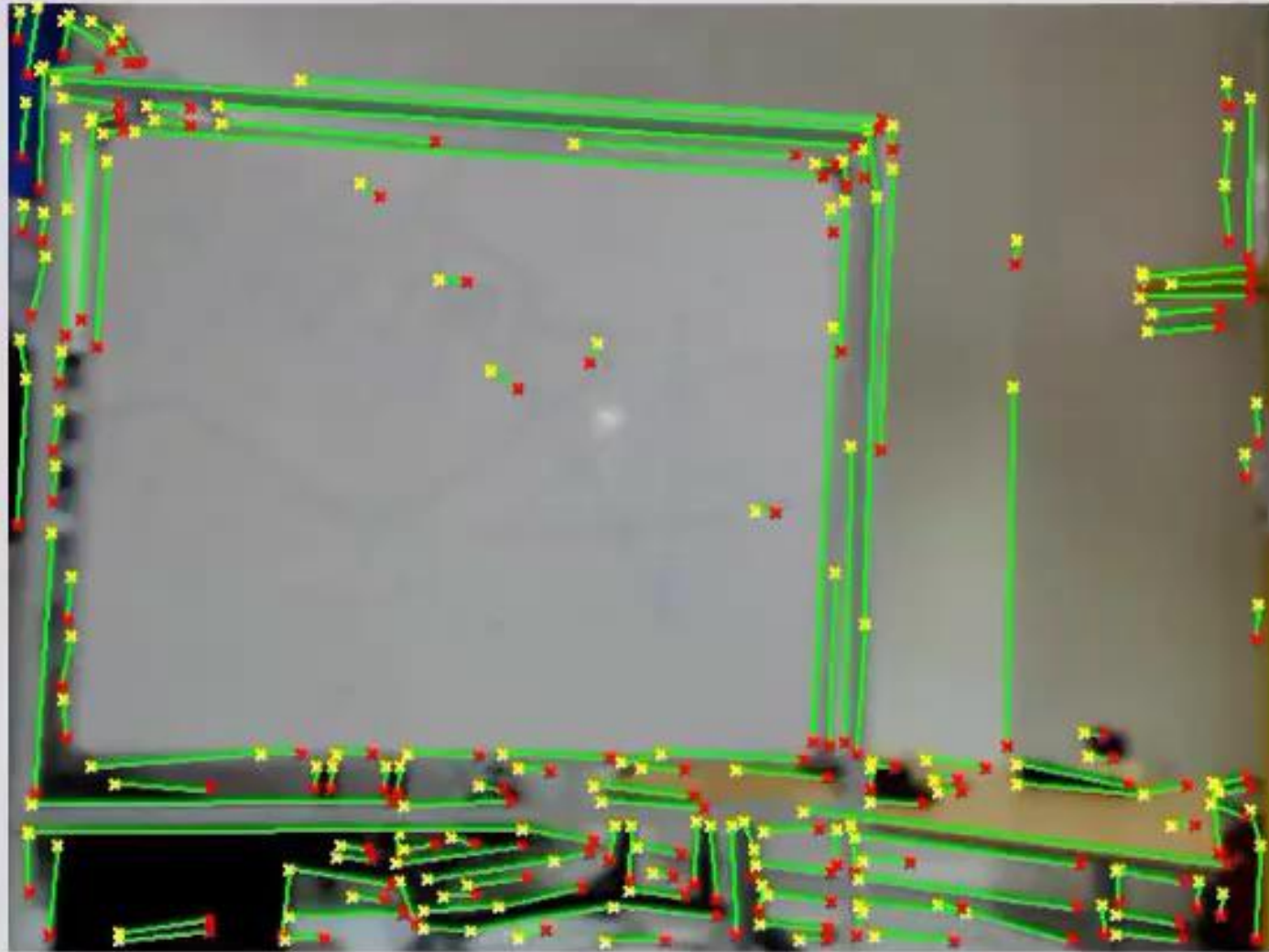
# SIMULATION OF 100X100 PIXEL MATRIX



CRUCIAL: S/N increases with resolution  $\rightarrow$  increase the number of degrees of freedom of the fit

- ▶ Find the circle: loop on  $x, R$
- ▶ 3D  $\rightarrow$  need to do slices in parametric space
- ▶ All the steps needed? **NO!!!!**
- ▶ **Interpolation in parametric space**

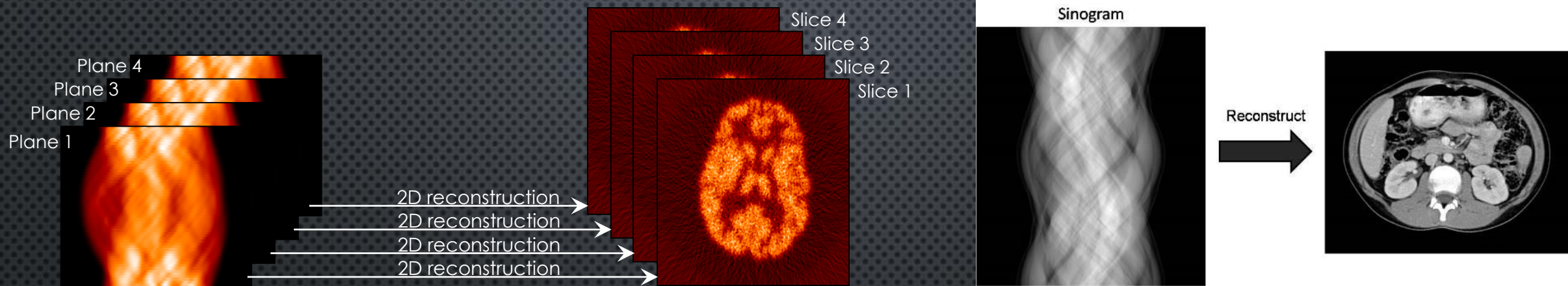






# MEDICAL APPLICATIONS?

- DATA REDUCTION IN MEDICAL IMAGING → SMART FRONT END FOR PET/CT?



THE SINOGRAM IS VERY MUCH SIMILAR TO THE HOUGH TRANSFORM AND THE WRM IS ESSENTIALLY A VERY FAST HOUGH TRANSFORMER (IN ITS BASIC VERSION)

- FOR PET → COULD BE USEFUL FOR CORRECTING FOR SMALL MOVEMENTS OF THE PATIENT?



# MEDICAL APPLICATIONS?

- HADRONTHERAPY → COULD BE USEFUL FOR KEEPING THE BEAM ON A MOVING TARGET?



- FOR INSTANCE IT COULD BE POSSIBLE TO TRACK THE ORGAN IN REAL TIME WITH MM PRECISION USING A FAST ARTIFICIAL VISION SYSTEM